


<b>Search Notes</b>  	<b>Application/Control No.</b>  10591269	<b>Applicant(s)/Patent Under Reexamination</b>  NAKANO ET AL.
	<b>Examiner</b>  SHIN-HON CHEN	<b>Art Unit</b>  2431

SEARCHED			
Class	Subclass	Date	Examiner
713	153, 165, 166, 189, 193	4/24/10	S.C.

SEARCH NOTES		
Search Notes	Date	Examiner
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search- see search history)	4/24/10	S.C.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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